

Atomistic Modeling of Phase-engineered MoS₂ Channel for the Decanometer Scale Digital Switches

Overview

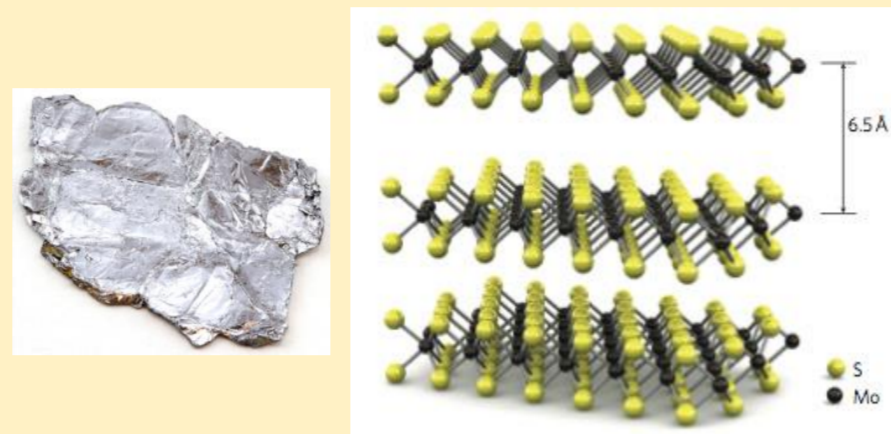
nature nanotechnology LETTERS
PUBLISHED ONLINE 30 JANUARY 2011 | DOI: 10.1038/NNANO.2010.279

Single-layer MoS₂ transistors

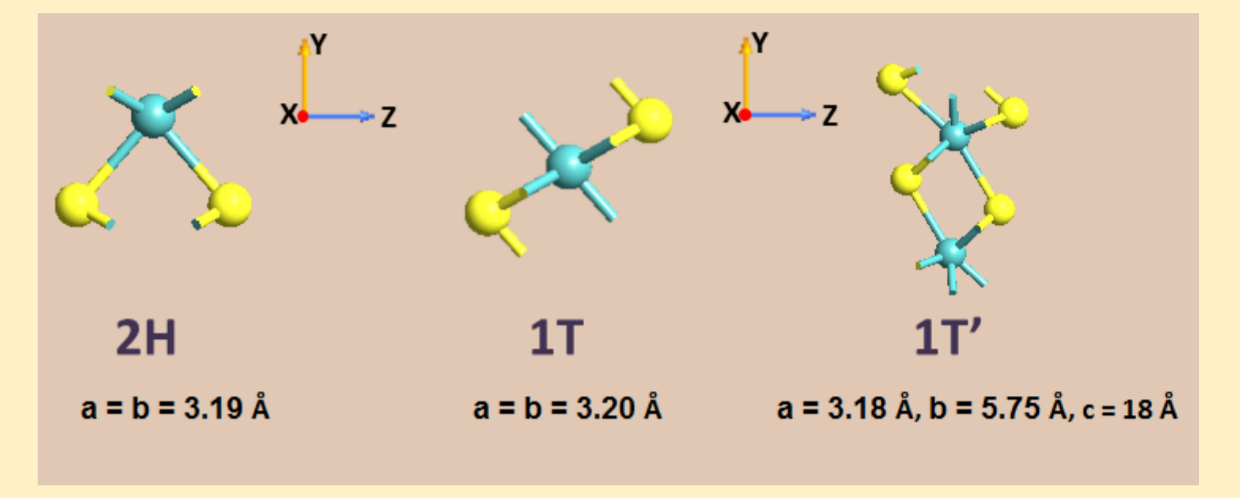
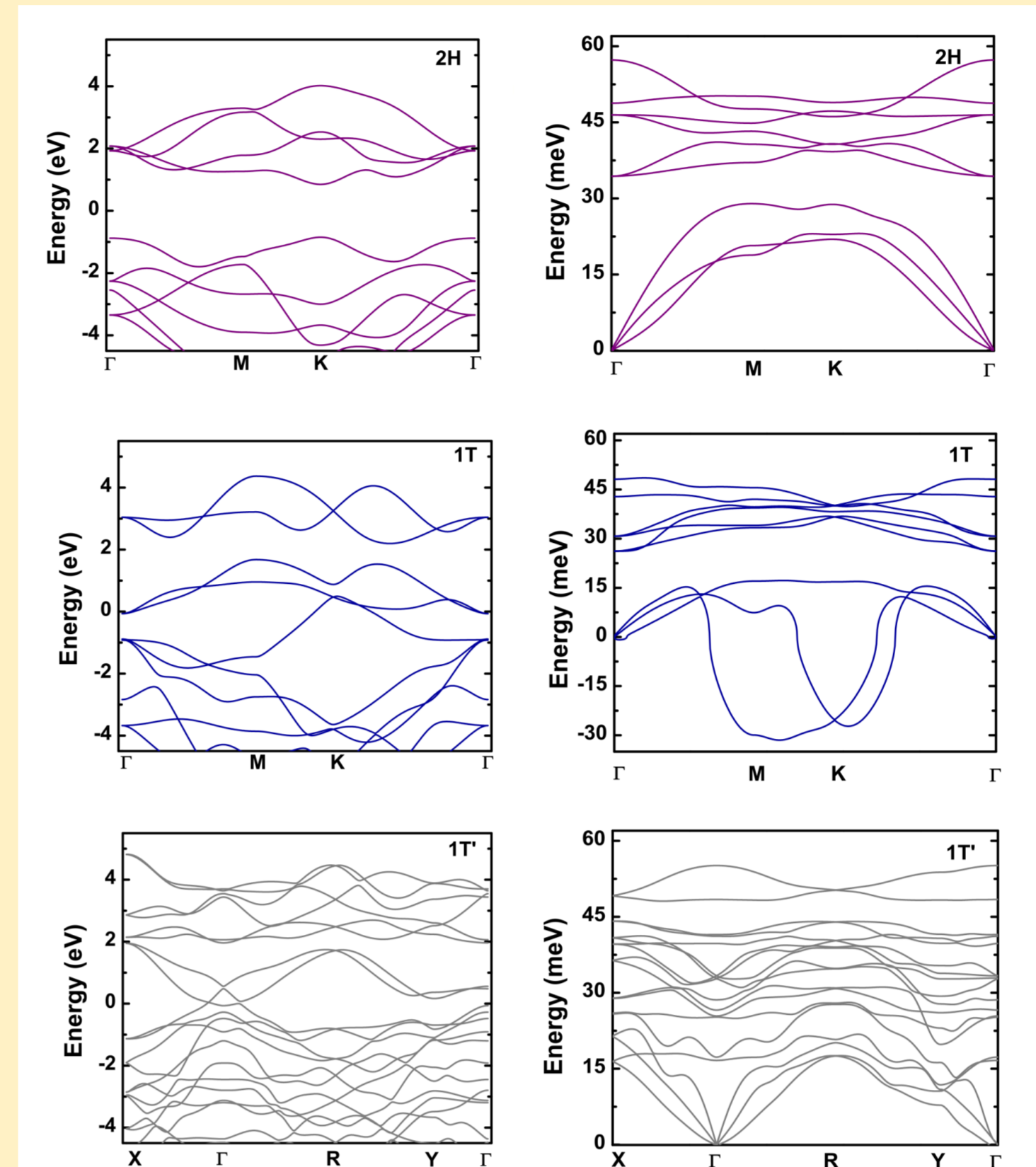
B. Radisavljevic¹, A. Radenovic², J. Brivio¹, V. Giacometti¹ and A. Kis^{1*}

Two-dimensional materials are attractive for use in next-generation nanoelectronic devices because, compared to one-dimensional materials, it is relatively easy to fabricate complex structures from them. The most widely studied two-dimensional material is graphene^{1,2}, both because of its rich physics³ and its high mobility⁴. However, pristine graphene does not have a bandgap, a property that is essential for many applications, including transistors. Engineering a graphene bandgap increases fabrication complexity and either reduces mobility to the level of strained silicon films^{5–8} or requires high voltages^{9,10}. Although single layers of MoS₂ have a large intrinsic bandgap of 1.8 eV (ref. 16), previously reported mobilities in the 0.5–3 cm² V⁻¹ s⁻¹ range¹¹ are too low for practical devices. Here, we use a hafnium oxide gate dielectric to demonstrate a room-temperature single-layer MoS₂ mobility of at least 400 cm² V⁻¹ s⁻¹ (ref. 20) are desirable.

The starting point for the fabrication of our transistors was scotch tape-based micromechanical exfoliation¹² of single-layer MoS₂. MoS₂ monolayers were transferred to degenerate-doped silicon substrates covered with 270-nm-thick SiO₂ (Fig. 2a). We have previously found that this oxide thickness is optimal for optical detection of single-layer MoS₂, and have established the correlation between contact and thickness as measured by atomic force microscopy (AFM)¹³. Electrical contacts were fabricated using electron-beam lithography followed by deposition of 50-nm-thick gold electrodes. The device was then annealed at 200 °C to remove residue¹⁴ and decrease contact resistance (for more details see Supplementary Information). At this point our single-layer devices show a typical mobility in the range 0.1–10 cm² V⁻¹ s⁻¹.



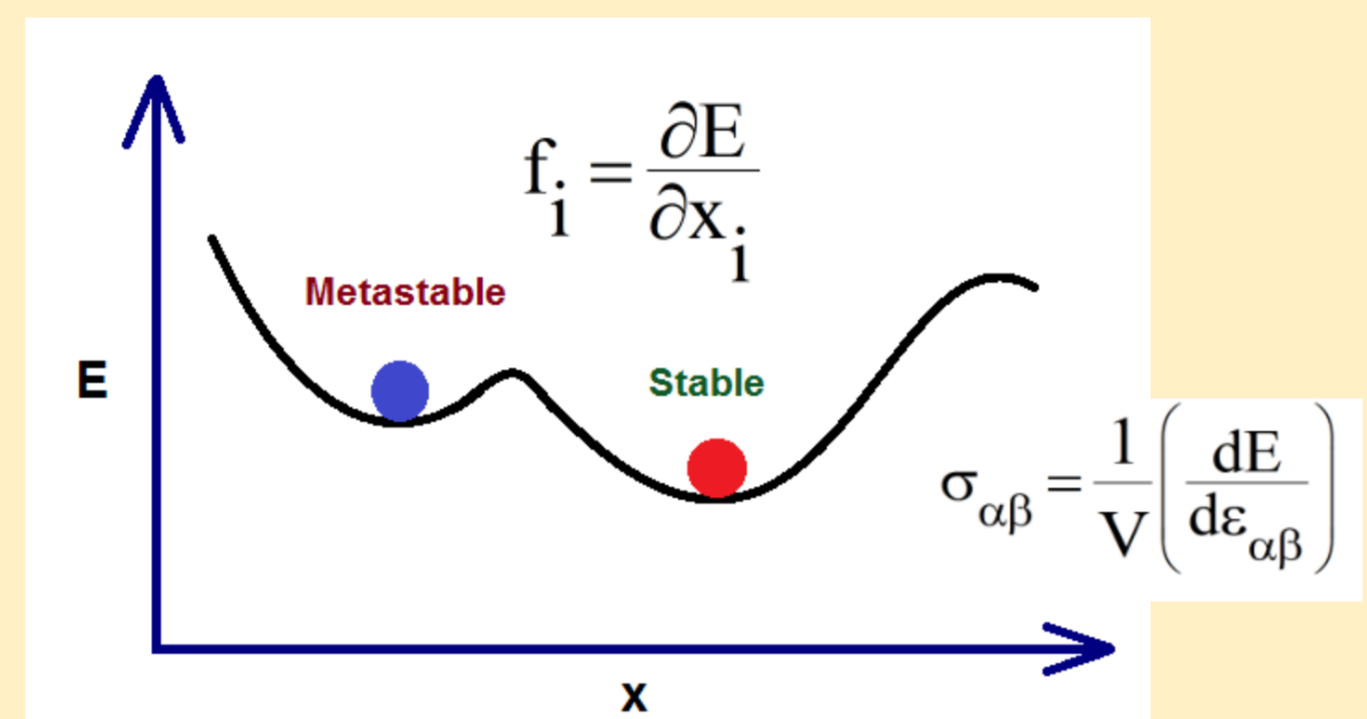
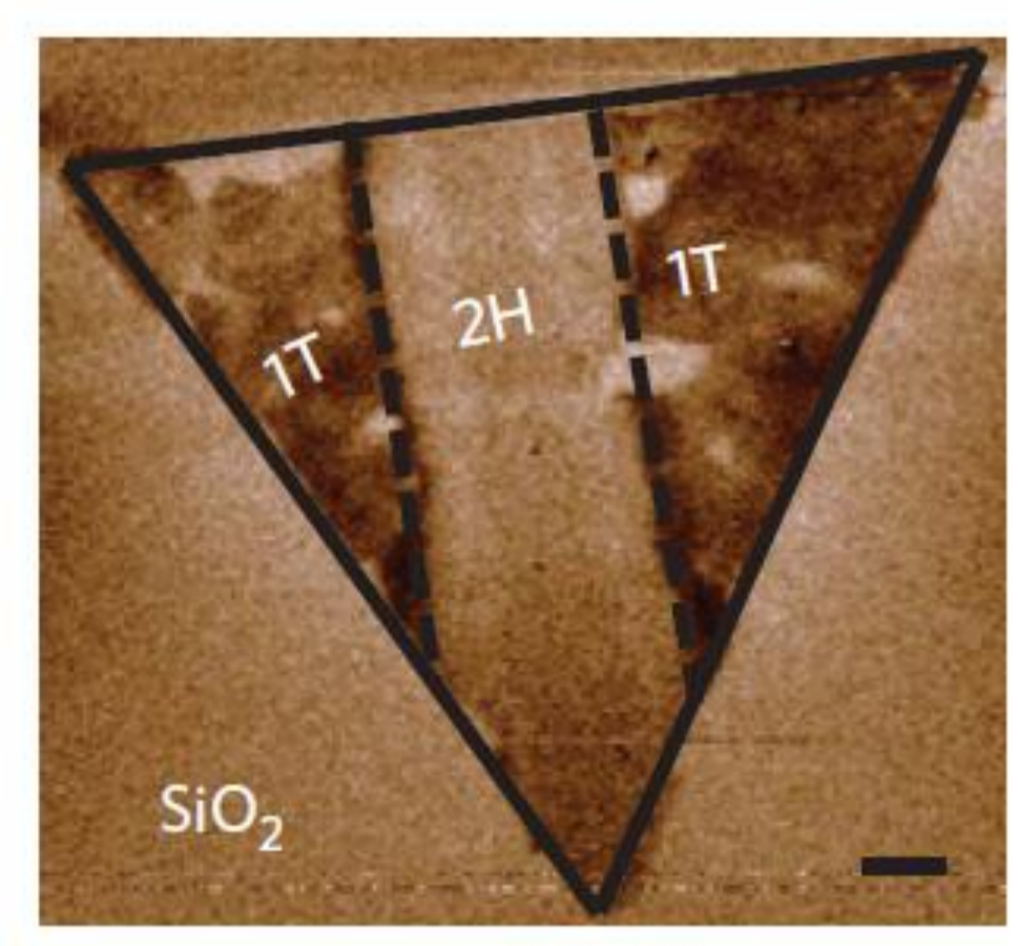
Abundance in nature and commonly used as lubricant



The 'Mo'-'Mo' distance at the β phase boundary is calculated as 2.76 Ang
Z-distance between 'Mo'-'Mo' atoms at the γ phase boundary is found to be 2.52 Ang

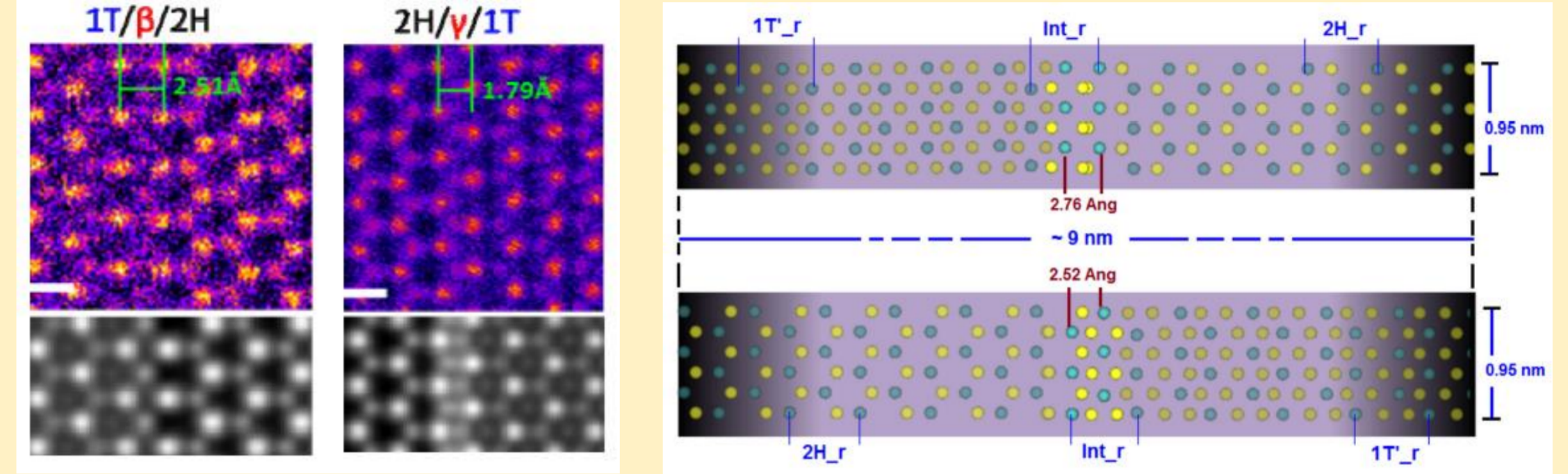
- Bandgap ~ 1.2 to 1.8 eV
- Thermal Conductivity(monolayer) @ RT ~ (34.5 ± 4) W/mK
- No dangling bonds
- Max. current density ~5×10⁷ A/cm²
50 times higher than Cu, But 5-10 times lower than graphene
- Stability up to 1100° C (in inert temp.)
- Effective mass
- Mobility

Ref:- B. Radisavljevic et al., Nat. Nanotech., 6, 2011
Ref:- Lembke and Kis, ACS Nano, 6, 11, 2012



Ref :- Rajesh Kappera et al., NATURE MATERIALS, vol. 13, 2014

- Devices with 1T phase electrodes ~ Show much better performance compared the devices with 2H phase contacts

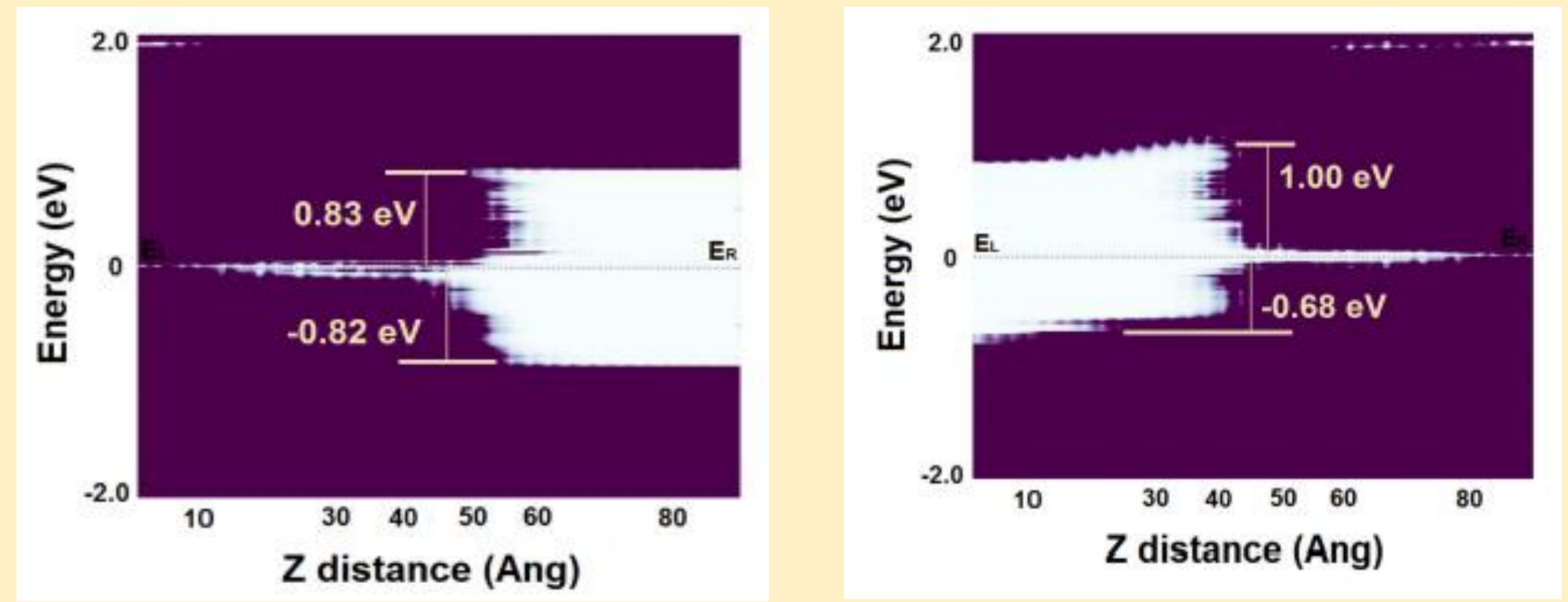
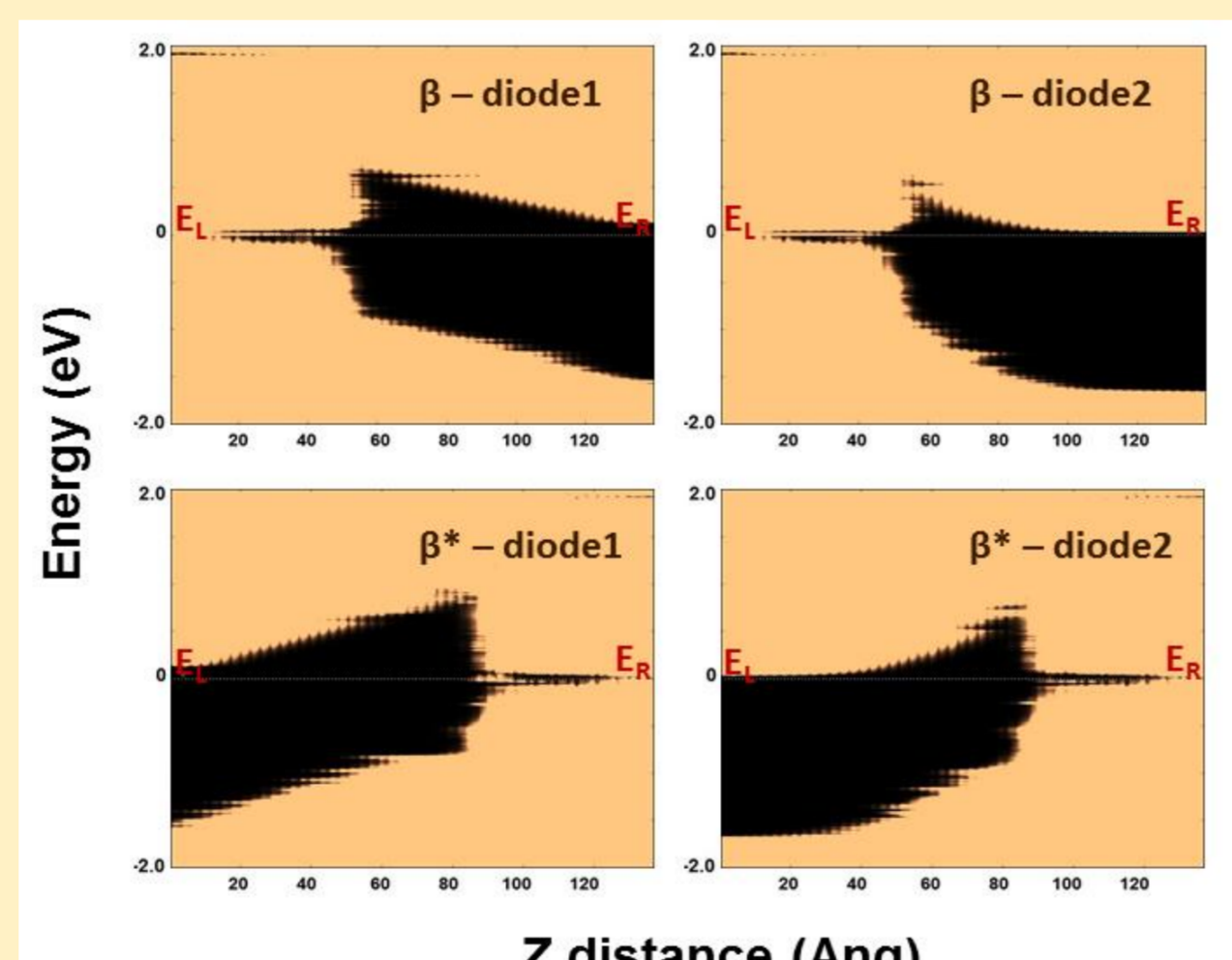
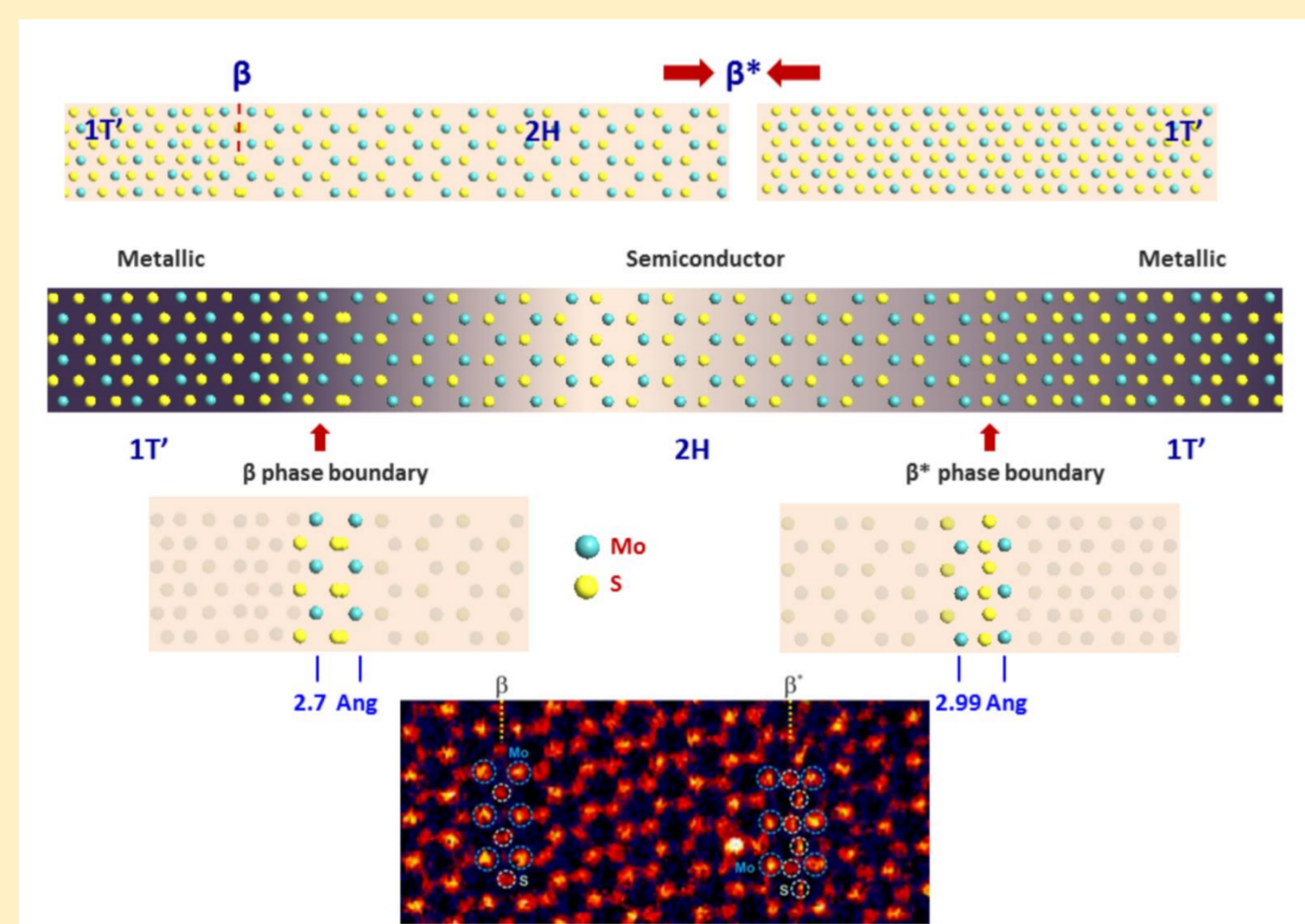


Atomistic models of the in-plane hetero-phase structures with β and γ phase boundaries

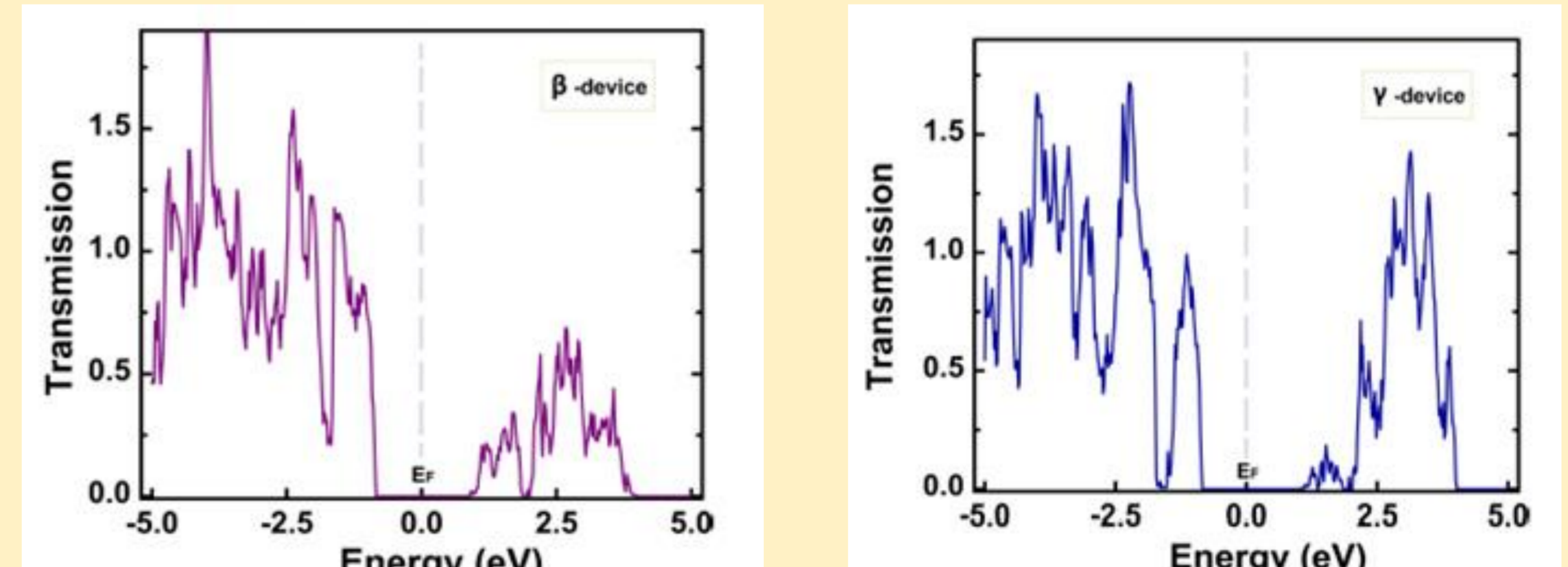
Ref :- D. Saha, S. Mahapatra, Applied Physics Letters, 108, 253106, 2016
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M-S-M heterophase MoS₂ structure

- Asymmetric Junctions in Metallic-Semiconducting-Metallic heterophase MoS₂ ~ atomic patterns at β and β* phase boundaries

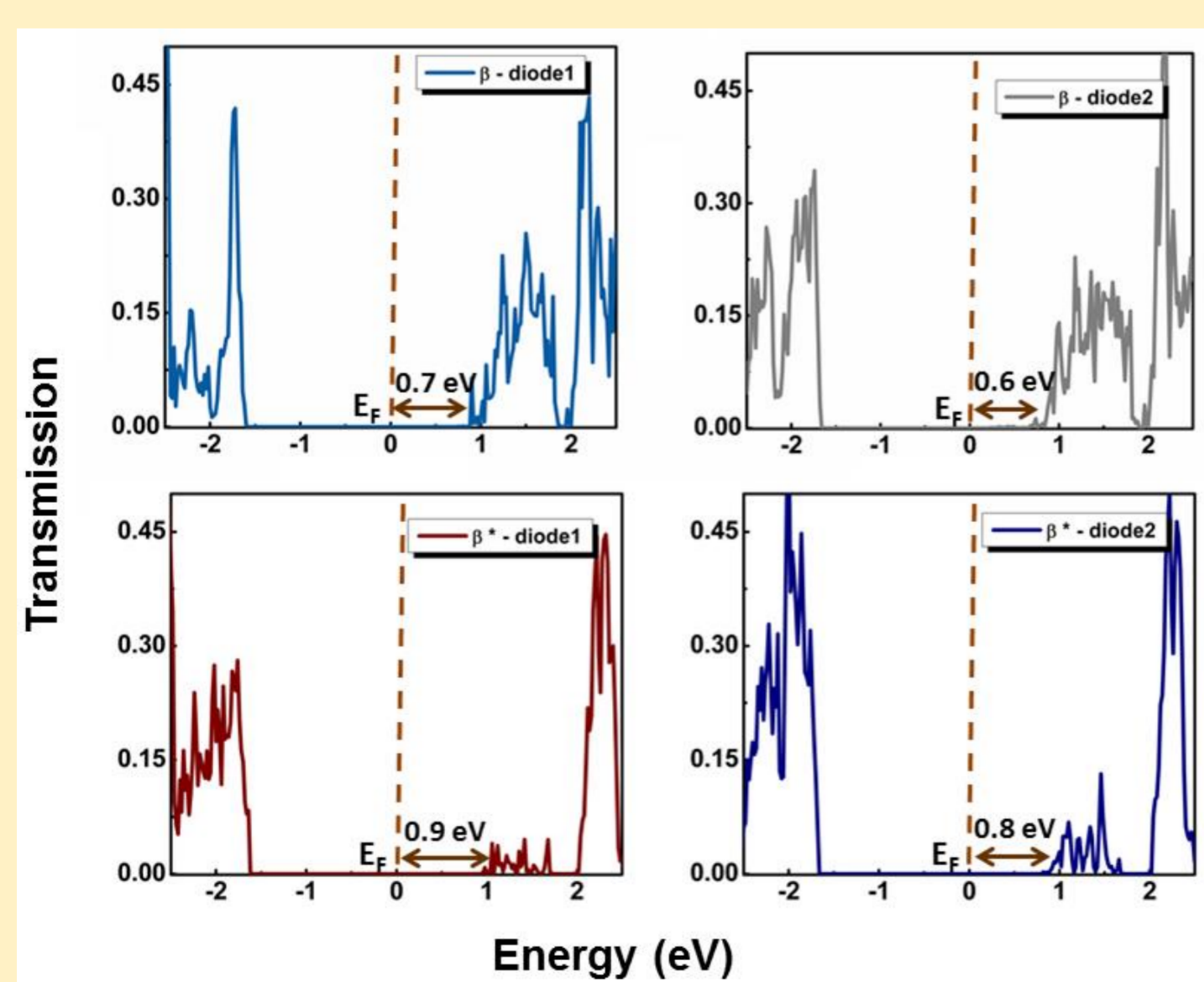


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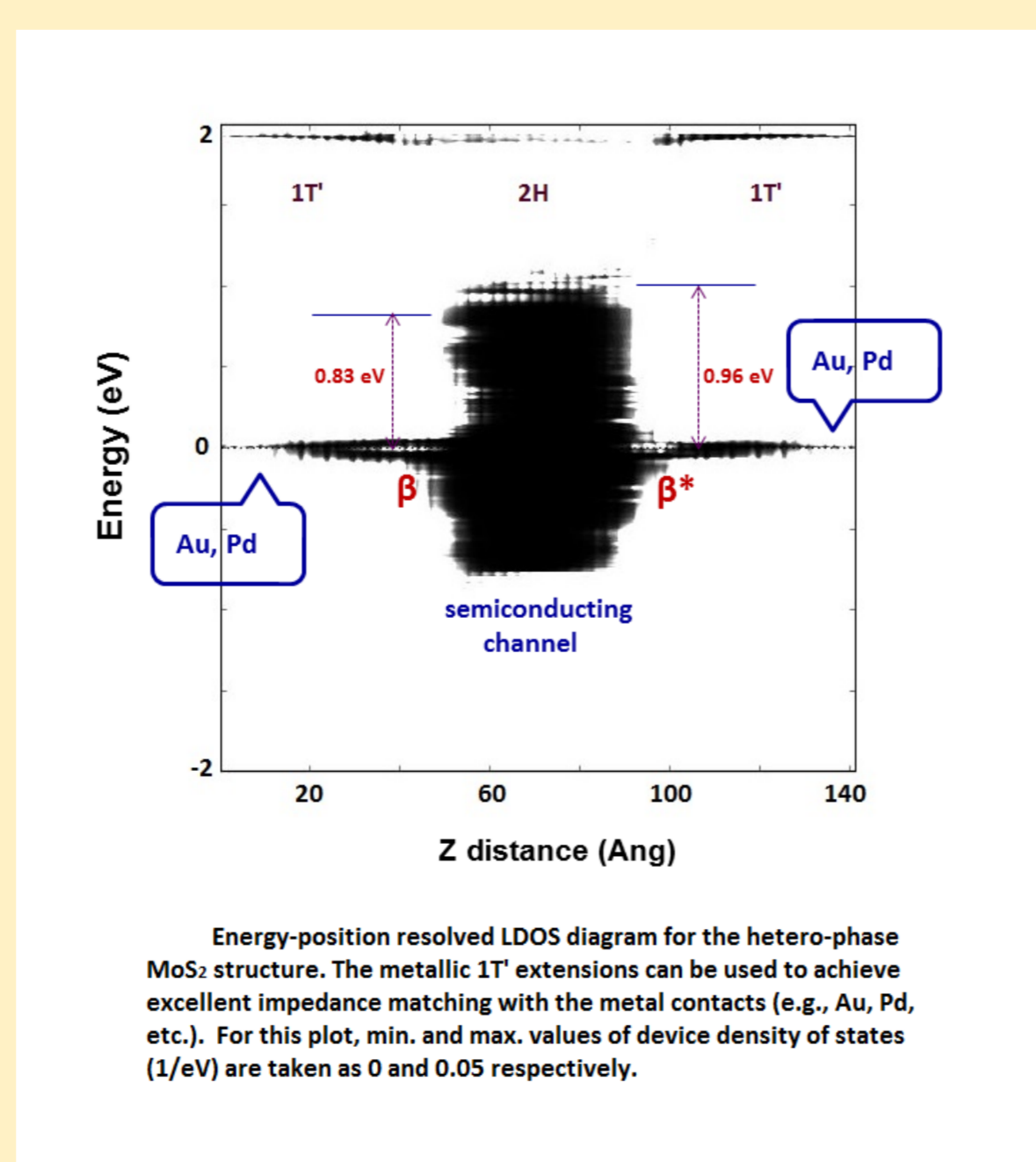


- Up-spin components of transmission spectra (obtained at zero bias) of the β-device and the γ-device respectively

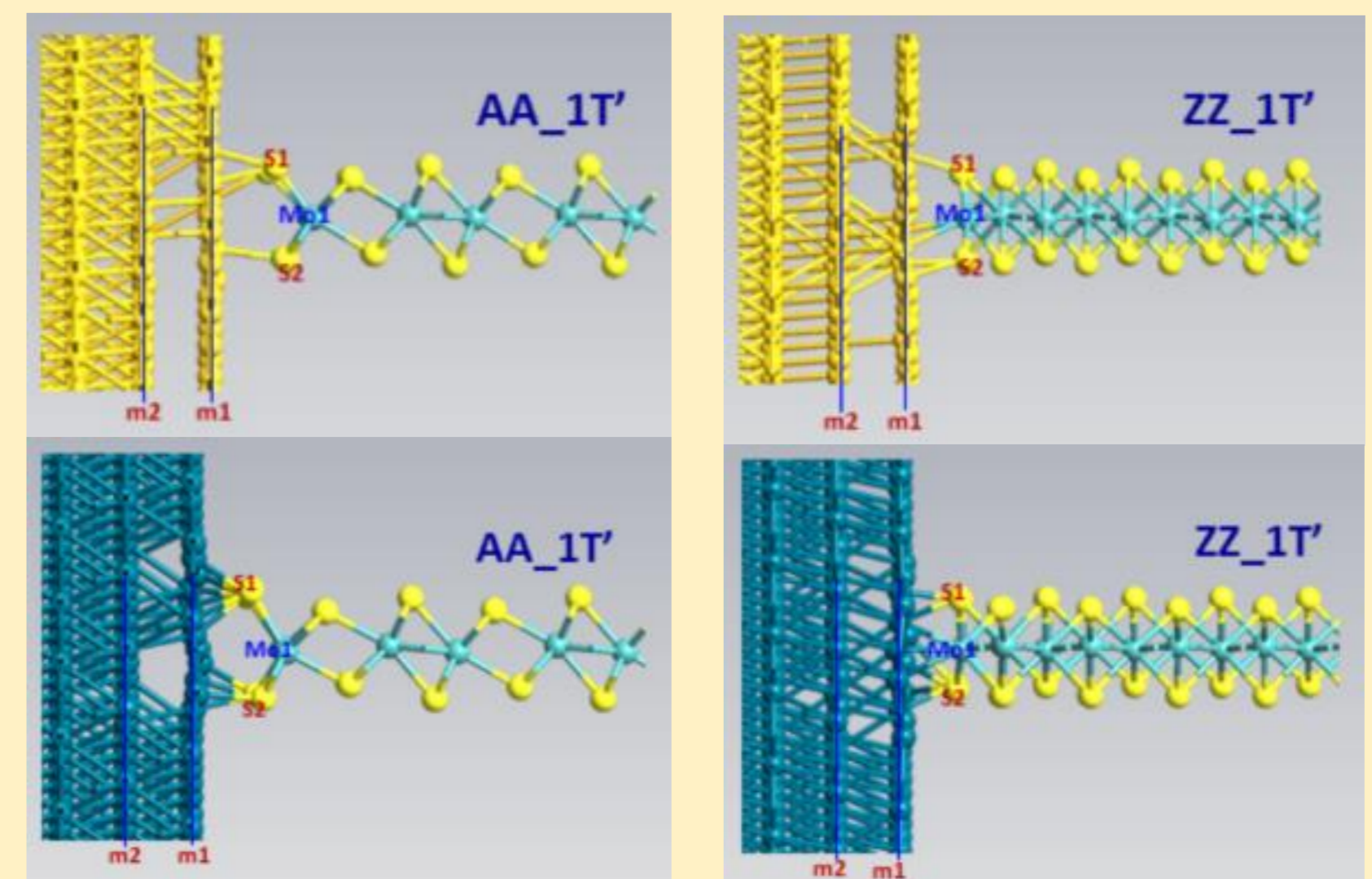
Ref :- D. Saha, S. Mahapatra, IEEE Transactions on Electron Devices, doi 10.1109/TED.2017.2680453
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Metal 1T' MoS₂ interfaces



Device structures	R (Ω.μm)
AA_1T'	55.9
Au_AA_1T'	293
Pd_AA_1T'	641
ZZ_1T'	18.3
Au_ZZ_1T'	37.08
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Ref :- D. Saha, S. Mahapatra, Physical Chemistry Chemical Physics, Royal Society of Chemistry

EECS Research Students
Symposium - 2017



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Dipankar Saha

PhD Student

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Indian Institute of Science,
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Introduction

nature
nanotechnology

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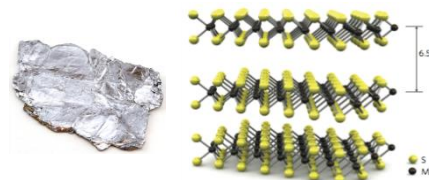
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I_{on}/I_{off} between 1×10^4 and 1×10^7 and a bandgap exceeding 400 meV (ref. 26) are desirable.

The starting point for the fabrication of our transistors was scotch tape-based micromechanical exfoliation^{11,17} of single-layer MoS₂. MoS₂ monolayers were transferred to degenerately doped silicon substrates covered with 270-nm-thick SiO₂ (Fig. 2a). We have previously found that this oxide thickness is optimal for optical detection of single-layer MoS₂, and have established the correlation between contrast and thickness as measured by atomic force microscopy (AFM)²⁷. Electrical contacts were fabricated using electron-beam lithography followed by deposition of 50-nm-thick gold electrodes. The device was then annealed at 200 °C to remove resist residue²⁸ and decrease contact resistance (for more details see Supplementary Information). At this point our single-layer devices show a typical mobility in the range 0.1–10 cm² V⁻¹ s⁻¹,



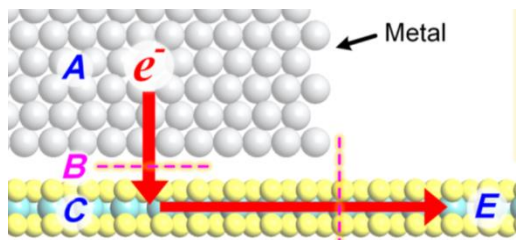
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- **No dangling bonds**
- **Max. current density ~5×10⁷ A/Cm²**
50 times higher than Cu, But 5-10 times lower than graphene
- **Stability up to 1100° C (in inert temp.)**
- **Effective mass**
- **Mobility**

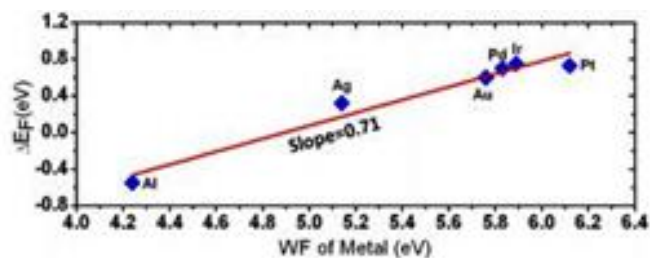
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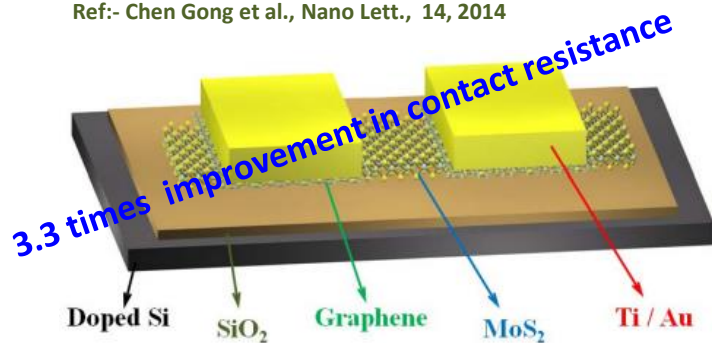
Introduction (cntd.)



Ref: - Jiahao Kang et al., PHYSICAL REVIEW X 4, 031005 (2014)



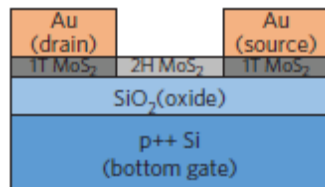
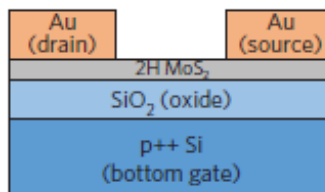
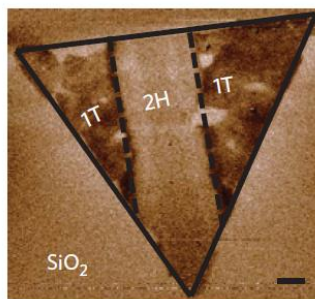
Ref:- Chen Gong et al., Nano Lett., 14, 2014



Ref:- Y. Du et al., IEEE Elec. Dev. Lett., 35, 5, 599-601, 2014

✓ Devices with 1T phase electrodes →

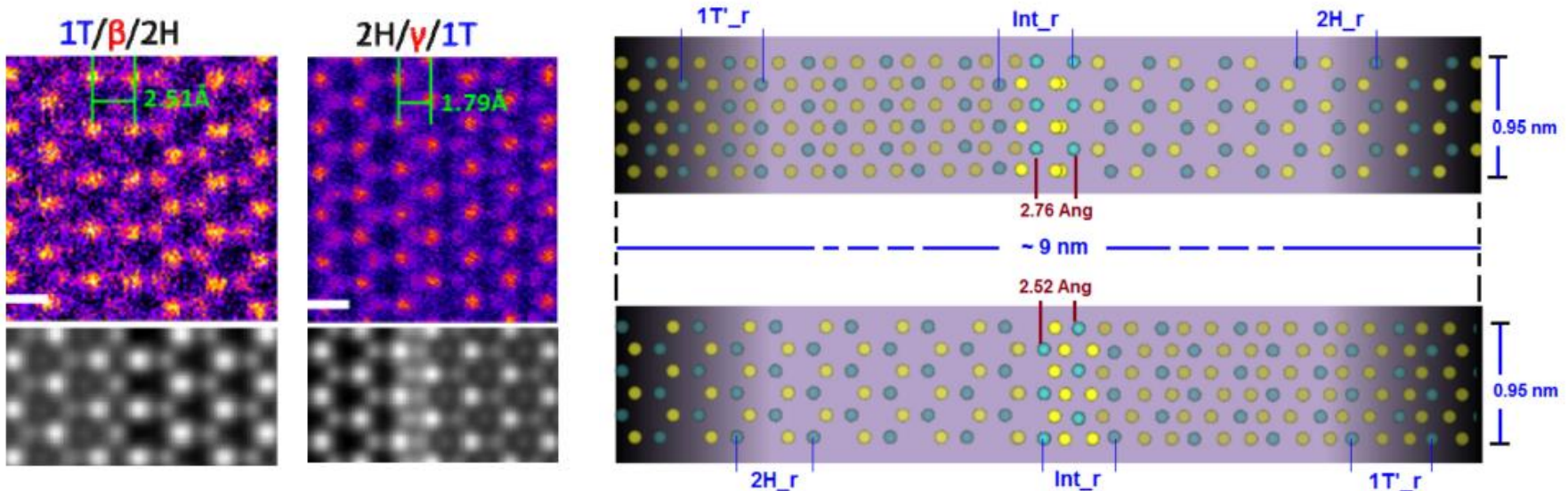
Show much better performance compared the devices with 2H phase contacts



Property	2H phase contacts	1T phase contacts
ON Current ($\mu\text{A} / \mu\text{m}$)	30	85
Transconductance ($\mu\text{S} / \mu\text{m}$)	1.4	3.8
Mobility ($\text{cm}^2/\text{V}\cdot\text{s}$)	19	46
ON / OFF ratio	10^7	10^8

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Metallic to Semiconducting Phase Boundaries



✓ Atomistic models of the in-plane hetero-phase structures with β and γ phase boundaries

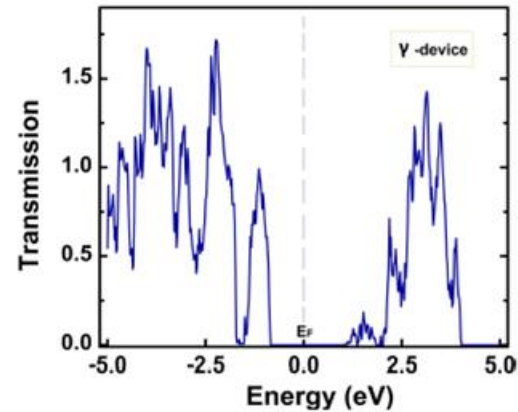
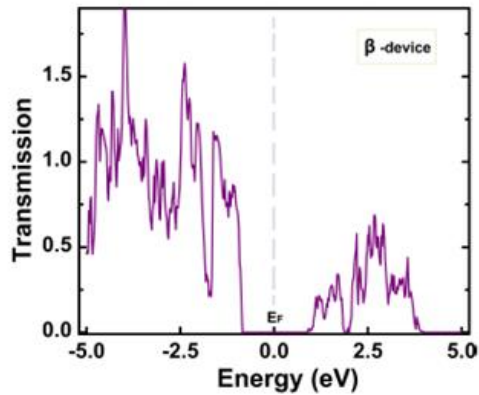
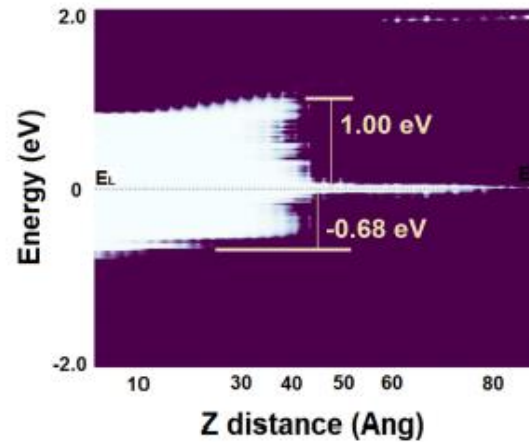
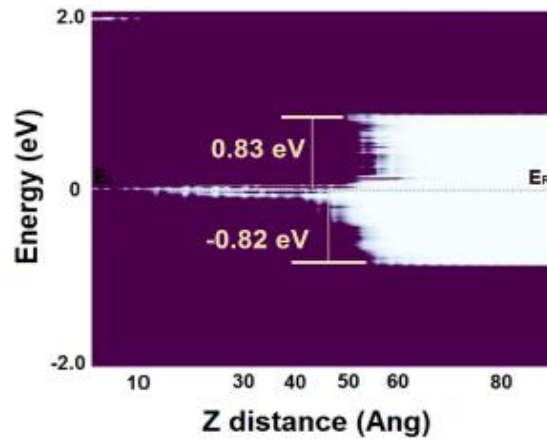
- The 'Mo'-'Mo' distance at the β phase boundary is calculated as 2.76 Å
- Z-distance between 'Mo'-'Mo' atoms at the γ phase boundary is found to be 2.52 Å

Perhaps, the slight differences in the 'Mo'-'Mo' distances at the boundaries, may have originated from the choice of our unit cells, lattice constants

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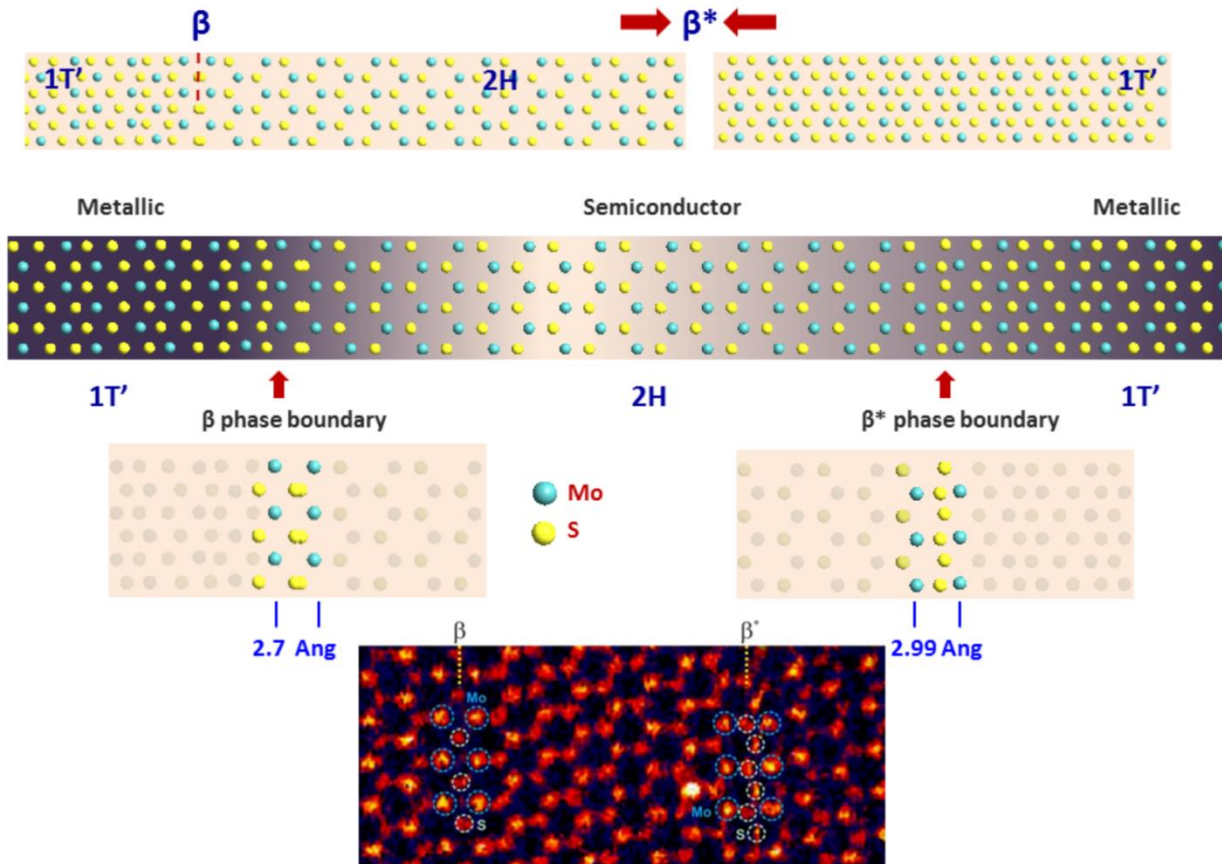
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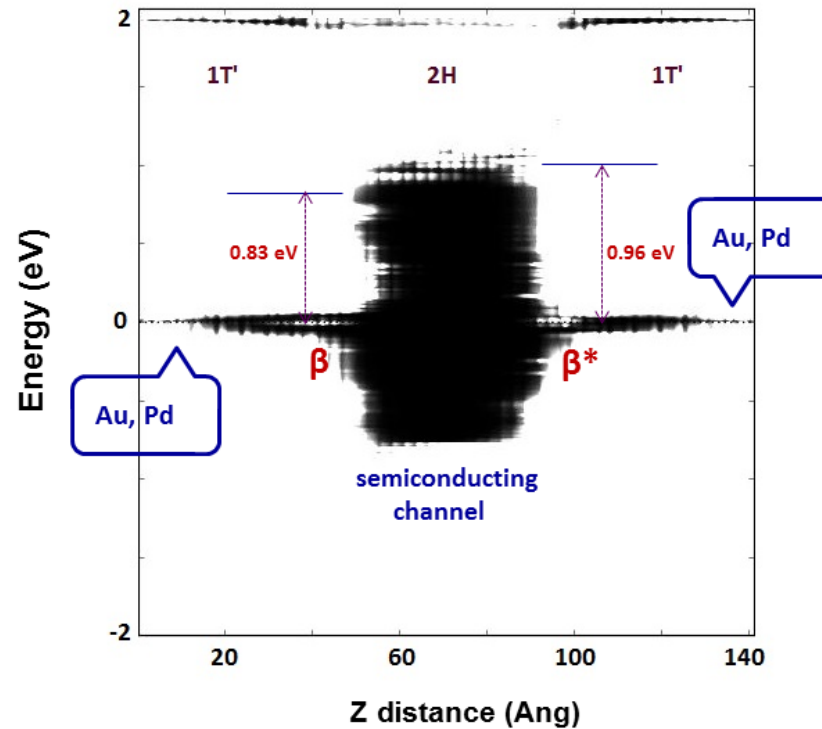
M-S-M hetero-phase MoS₂



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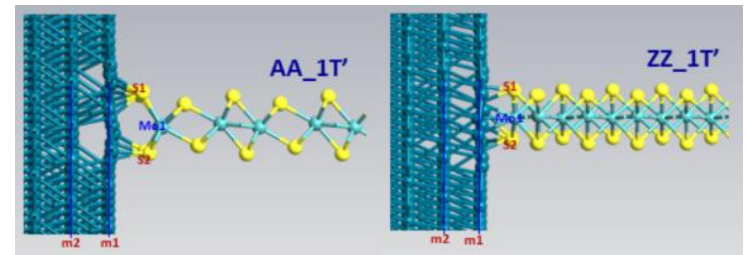
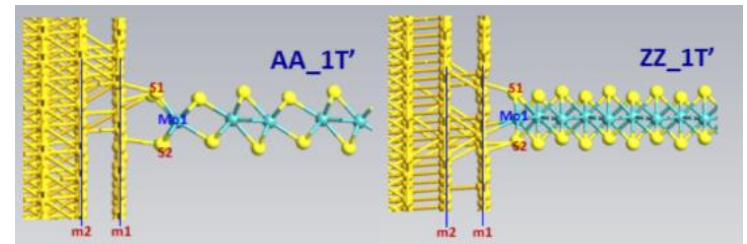
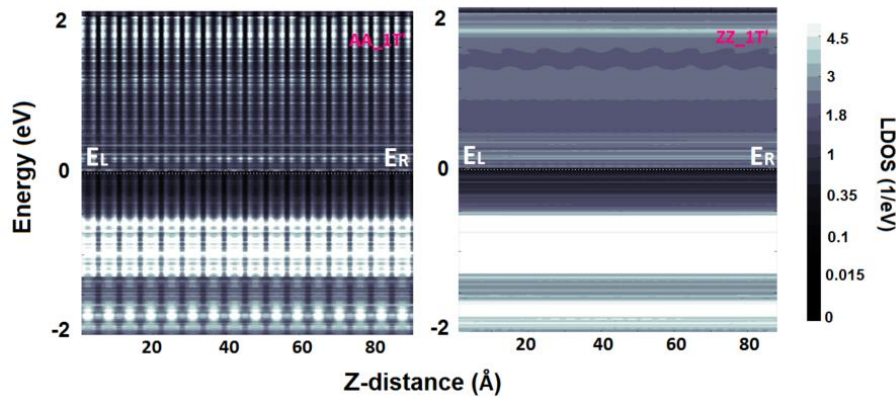
Ref :- Y-C. Lin, D. O. Dumcenco, Y-S. Huang, and K. Suenaga, *Nature Nanotechnology*, 9, 2014

M-S-M hetero-phase MoS₂ (Cntd.)



Energy-position resolved LDOS diagram for the hetero-phase MoS₂ structure. The metallic 1T' extensions can be used to achieve excellent impedance matching with the metal contacts (e.g., Au, Pd, etc.). For this plot, min. and max. values of device density of states (1/eV) are taken as 0 and 0.05 respectively.

1T' monolayer MoS₂ and its metal interfaces



Device structures	R ($\Omega \cdot \mu m$)
AA_1T'	55.9
Au_AA_1T'	293
Pd_AA_1T'	641
ZZ_1T'	18.3
Au_ZZ_1T'	37.08
Pd_ZZ_1T'	38.6

Ref :- D. Saha, S. Mahapatra, Physical Chemistry Chemical Physics, (Under Review)

Summary

- ✓ We have designed Atomistic Model of the planar hetero-phase structures of monolayer MoS₂, having two disparate phase transition regions
- ✓ We explored Asymmetric Junctions in M-S-M hetero-phase structure, and obtained the charge carrier transport through the β and β^* phase boundaries
- ✓ We have also investigated the orientation dependent charge carrier transport in the metal (Au and Pd) interfaces of 1T' MoS₂

- The key advantage of such devices is their 1T' extension region which can effectively be contacted with various metals for significantly reducing the Schottky-limited transport

Thank You